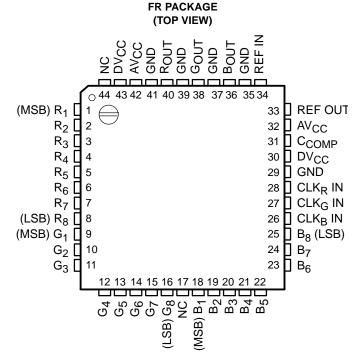
- 8-Bit Resolution
- Linearity . . . ± 1/2 LSB Maximum
- Differential Nonlinearity . . . ±1/2 LSB Maximum
- Conversion Rate . . . 60 MHz Min
- Nominal Output Signal Operating Range V<sub>CC</sub> to V<sub>CC</sub> – 1 V
- TTL Digital Input Voltage
- 5-V Single Power Supply Operation
- Low Power Consumption . . . 350 mW Typ

#### description

0°C to 70°C.

The TL5632C is a low-power ultra-high-speed video digital-to-analog converter that uses the Advanced Low-Power Schottky (ALS) process. The device has a three channel I/O; the red, the blue, and the green channel. The red, blue, and green signals are referred to collectively as the RGB signal. An internally generated reference is also provided for the standard video output voltage range. Conversion of digital signals to analog signals can be at a sampling rate of dc to 60 MHz. The high conversion rate makes the TL5632C suitable for digital television, computer digital video processing, and high-speed data conversion.

The TL5632C is characterized for operation from



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NC - No internal connection

FUNCTION TABLE						
STEP	DIGITAL INPUT	OUTPUT VOLTAGE				
0	LLLLLLL	3.980 V				
1	LLLLLLH	3.984 V				
•	•	•				
•	•	•				
•	•	•				
127	LHHHHHHH	4.488 V				
128	HLLLLLL	4.492 V				
129	HLLLLLH	4.996 V				
•	•	•				
•	•	•				
•	•	•				
254	HHHHHHL	4.996 V				
255	ннннннн	5.000 V				

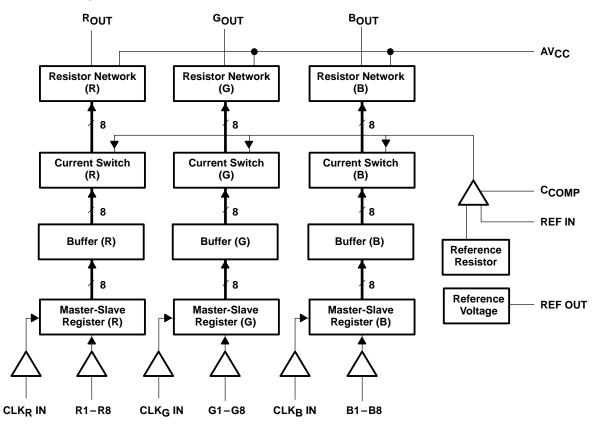
#### **AVAILABLE OPTIONS**

Т <sub>А</sub>	PACKAGE		
0°C to 70°C	TL5632CFR		

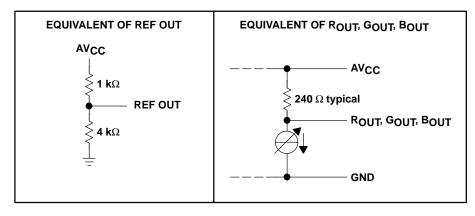


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### functional block diagram



### schematics of outputs





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### **Terminal Functions**

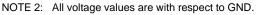
TERMINAL			DECODIDION		
NAME	NO.	1/0	DESCRIPTION		
B <sub>1</sub> – B <sub>8</sub>	18 – 25	I	B-channel digital input (B <sub>1</sub> = MSB)		
BOUT	36	0	B-channel analog output		
CCOMP	31		Phase compensation capacitance. A 1 $\mu F$ capacitor is connected from C_COMP to GND.		
CLK <sub>B</sub> IN	26	Ι	B-channel clock input		
CLK <sub>G</sub> IN	27	Ι	G-channel clock input		
CLK <sub>R</sub> IN	28	Ι	R-channel clock input		
G <sub>1</sub> – G <sub>8</sub>	9 – 16	Ι	G-Channel digital input (G1= MSB)		
GND	29, 35, 37, 39, 41		Ground. All GND terminals are connected internally; however, all GND terminals should be connected externally to a ground plane or equivalent low impedance ground return.		
GOUT	38	0	G-channel analog output		
NC	17, 44		No connection internally		
R <sub>1</sub> – R <sub>8</sub>	1 – 8	I	R-channel digital input (R <sub>1</sub> = MSB)		
ROUT	40	0	R-channel analog output		
AVCC	32, 42		Analog power supply voltage		
DVCC	30, 43		Digital power supply voltage		
REF IN	34	I	Reference voltage input. REF IN accepts the reference voltage on REF OUT. An external reference can also be applied consistent with Note 1.		
REF OUT	33	0	Reference voltage output. An internal voltage divider generates the voltage level (see schematics of outputs, page 2).		

NOTE 1:  $V_{CC} - V_{ref} \le 1.2 \text{ V}$ 

### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)<sup>†</sup>

Power supply voltage range, AV <sub>CC</sub> , DV <sub>CC</sub> (see Note 2)	$\ldots$ $-0.3$ V to 7 V
Digital input voltage range, V <sub>1</sub>	$\dots \dots \dots \dots \dots -0.3$ V to DV <sub>CC</sub>
Analog output voltage range, ROUT, GOUT, BOUT, CCOMP (externational strength of the strength o	ally applied) $\dots -0.3$ V to AV <sub>CC</sub> + 0.3 V
Reference input range, REF IN	$\dots \dots \dots \dots -0.3 \text{ V to AV}_{CC} + 0.3 \text{ V}$
Reference output range, REF OUT	$\dots \dots \dots \dots -0.3 \text{ V to AV}_{CC} + 0.3 \text{ V}$
Operating free-air temperature range, T <sub>A</sub>	0°C to 70°C
Storage temperature range	
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds .	

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.





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### recommended operating conditions

	MI	N	NOM	MAX	UNIT
Supply voltage, AV <sub>CC</sub> , DV <sub>CC</sub>	4.7	5	5	5.25	V
High-level input voltage, VIH		2			V
Low-level input voltage, VIL				0.8	V
Reference voltage, V <sub>ref</sub> (see Note 1)	3.	8	4	4.2	V
Setup time, data before CLK <sup>↑</sup> , t <sub>su1</sub>	1	0			ns
Hold time, data after CLK↑, t <sub>h1</sub>		3			ns
Pulse duration at high level, tw1	8.	3			ns
Pulse duration at low level, tw2	8.	3			ns
External phase compensation capacitance, CCOMP		1			μF
Operating free-air temperature, T <sub>A</sub>		0		70	°C

NOTE 1:  $V_{CC} - V_{ref} \le 1.2 \text{ V}$ 

#### electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

	PARAMETER	TEST	CONDITIONS	MIN	TYP†	MAX	UNIT
	Resolution					8	Bit
Чн	High-level input current	V <sub>CC</sub> = 5.25 V,	V <sub>IH</sub> = 2.7 V			20	μA
۱ <sub>IL</sub>	Low-level input current	V <sub>CC</sub> = 5.25 V,	V <sub>IH</sub> = 2.7 V	-400			μA
I <sub>ref</sub>	Reference input current	REF IN = 4 V				10	μA
V <sub>ref</sub>	Reference output voltage	V <sub>CC</sub> = 5 V,	With internal reference	3.8	4	4.2	V
VFS	Full-scale analog output voltage	V <sub>IH</sub> = 2 V,	REF IN = 4 V	AV <sub>CC</sub> -15	AVCC	AV <sub>CC</sub> +15	mV
Vzs	Zero-scale analog output voltage	V <sub>IL</sub> = 0.8 V,	REF IN = 4 V	3.9	3.98	4.05	V
	RGB full-scale ratio			0%	4%	8%	
z <sub>0</sub>	Output impedance			200	240	280	W
ICC	Supply current				70	90	mA

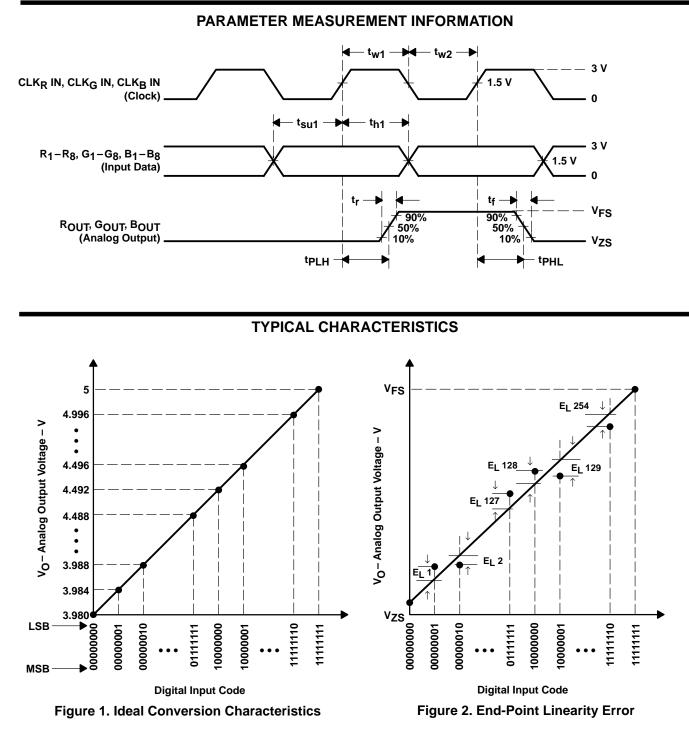
### operating characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP <sup>†</sup>	MAX	UNIT
EL	Linearity error	End point, REF IN = 4 V			±0.5	LSB
ED	Differential linearity error	REF IN = 4 V			±0.5	LSB
f <sub>C</sub>	Maximum conversion rate		60			MHz
<sup>t</sup> PLH	Propagation delay time, low-to-high level			10		20
<sup>t</sup> PHL	Propagation delay time, high-to-low level	T <sub>A</sub> = 25°C, C <sub>I</sub> ≤ 5 pF <sup>‡</sup>		10		ns
tr	Rise time	$ A  = 250,  CL \le 5 \text{ pr}^{+}$		5		ns
tf	Fall time			5		115

<sup>†</sup> All typical values are at V<sub>CC</sub> = 5 V, T<sub>A</sub> = 25°C. <sup>‡</sup>C<sub>L</sub> includes probe and jig capacitances.



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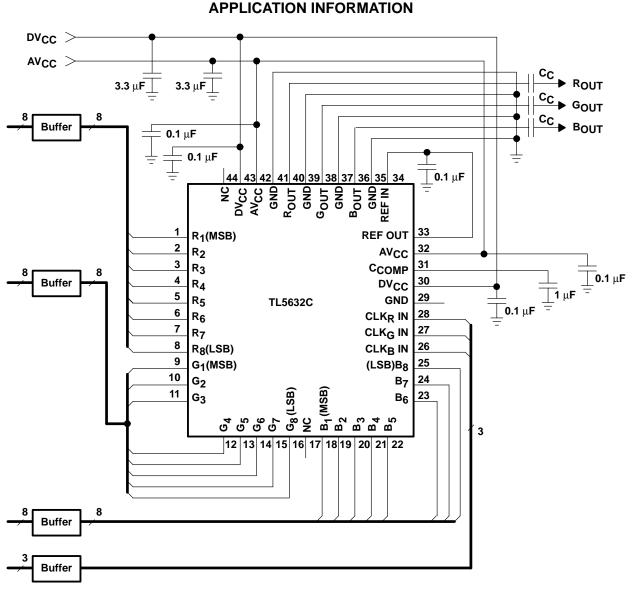
### **APPLICATION INFORMATION**

The following design procedures should be used for optimum operation.

- External analog and digital circuitry should be physically separated and shielded as much as possible to reduce system noise.
- RF breadboarding or RF printed-circuit-board (PCB) techniques should be used throughout the evaluation and production process.
- Wide ground leads or a ground plane should be used on the PCB layouts to minimize parasitic inductance and resistance. A ground plane is the better choice for noise reduction.
- AV<sub>CC</sub> and DV<sub>CC</sub> are also separate internally, so they must be connected externally. These external PCB leads should also be made as wide as possible. A ferrite bead or equivalent inductance should be placed in series with AV<sub>CC</sub> and the decoupling capacitor before the AV<sub>CC</sub> and DV<sub>CC</sub> leads are connected together on the board. It is critical that the supply voltage applied to AV<sub>CC</sub> be as noise free and ripple free as possible. Ripple and noise rejection should be a minimum of 60 dB below the full-scale output range of 1 V peak-to-peak.
- AV<sub>CC</sub> to GND and DV<sub>CC</sub> to GND should be decoupled with 3.3-μF and 0.1-μF capacitors, respectively, as close as possible to the appropriate device terminals. A ceramic chip capacitor is recommended for the 0.1-μF capacitor.
- The phase compensation capacitor should be connected between C<sub>COMP</sub> and GND with as short a lead-in as possible.
- The no-connection (NC) terminals on the small-outline package should be connected to GND.
- AV<sub>CC</sub>, DV<sub>CC</sub>, and R<sub>OUT</sub>, G<sub>OUT</sub>, and B<sub>OUT</sub> should be shielded from the high-frequency terminals CLK<sub>R</sub> IN, CLK<sub>G</sub> IN, and CLK<sub>B</sub> IN and the input data terminals. GND traces should be placed on both sides of the R<sub>OUT</sub>, G<sub>OUT</sub>, and B<sub>OUT</sub> traces on the PCB to the following signal processing stage. These output traces should be as short as possible.



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NOTES: A. Buffers are SN74AS244 or equivalent.

B. 0.1  $\mu\text{F}$  capacitors should be placed as close to the device terminals as possible.

C. The coupling capacitor (C\_C) value is application specific and selectable by the user.

Figure 3. Typical Bypass, Buffer, and Output Configuration

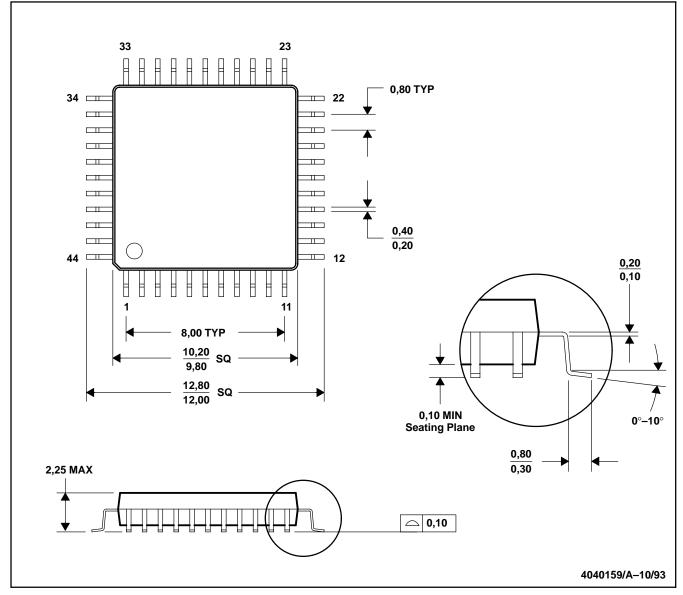


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**MECHANICAL DATA** 

FR/S-PQFP-G44

PLASTIC QUAD FLATPACK



NOTES: A. All linear dimensions are in millimeters.

B. This drawing is subject to change without notice.



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